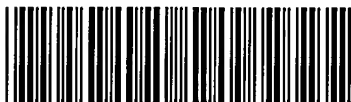


**Search Notes**

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10/630,977

Examiner

TAN X. DINH

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2627

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see search history printout)	1/30/2007	T.D